

TMUX405x-Q1 具有 1.8V 逻辑电平的汽车类 24V、8:1 单通道、4:1 双通道多路复用器

1 特性

- 符合面向汽车应用的 AEC-Q100 标准
 - 器件温度等级 1：-40°C 至 125°C 的工作环境温度范围
- 双电源电压范围：±3V 至 ±12V
- 单电源电压范围：3V 至 24V
- 55°C 至 +125°C 工作温度
- 先断后合开关
- ESD 保护 HBM：2000V
- TMUX405x - 与以下器件引脚兼容：
 - 业界通用的 4051 和 4052 多路复用器

2 应用

- 模拟多路复用和多路信号分离
- 数字多路复用和多路信号分离
- 电池管理系统 (BMS)
- HVAC 控制模块
- 汽车音响主机
- 远程信息处理系统
- 车载充电器 (OBC) 和无线充电

3 说明

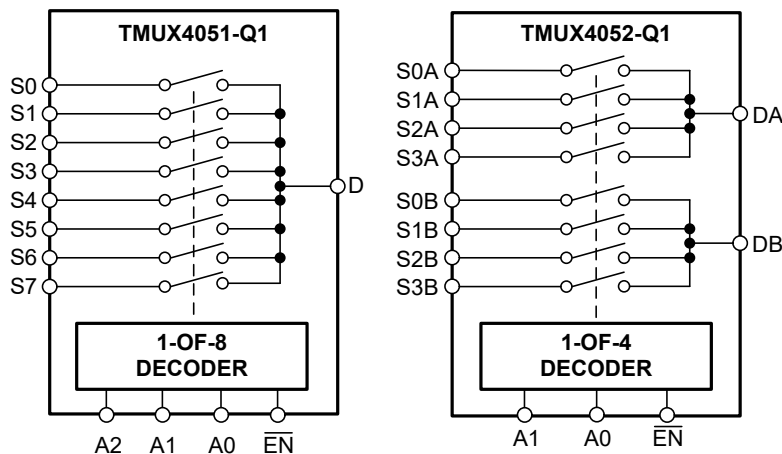
TMUX405x-Q1 器件是通用互补金属氧化物半导体 (CMOS) 多路复用器 (MUX)。TMUX4051-Q1 是一款 8:1、单通道多路复用器，TMUX4052-Q1 是一款 4:1、双通道多路复用器。这些器件由单电源 (3V 至 24V)、双电源 (±3V 至 ±12V) 或非对称电源 (例如 $V_{DD} = 12V$, $V_{SS} = -5V$) 供电。宽电源电压范围支持 TMUX405x-Q1 器件用于从工厂自动化到电器的各种应用。

TMUX405x-Q1 器件可支持源极 (Sx) 和漏极 (Dx) 引脚上从 V_{SS} 到 V_{DD} 范围的双向模拟和数字信号。所有逻辑输入均具有兼容 1.8 V 逻辑的阈值，在有效电源电压下运行时，这些阈值可确保 TTL 和 CMOS 逻辑兼容性。

器件信息⁽¹⁾

器件型号	封装	封装尺寸 (标称值)
TMUX4051-Q1 TMUX4052-Q1	TSSOP (16)	5.00mm × 4.40mm
	SOT-23-THIN (16)	4.20 mm × 2.00 mm
	WQFN (16)	3.50mm × 2.50mm

(1) 如需了解所有可用封装，请参阅数据表末尾的封装选项附录。



TMUX4051-Q1 and TMUX4052-Q1 方框图



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4 Revision History

DATE	REVISION	NOTES
June 2022	*	Initial Release

5 Device Comparison Table

PRODUCT	DESCRIPTION
TMUX4051-Q1	8:1, 1-channel multiplexer
TMUX4052-Q1	4:1, 2-channel multiplexer

6 Pin Configuration and Functions

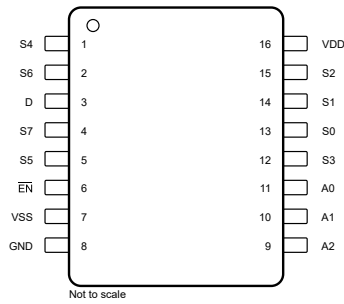


图 6-1. TMUX4051-Q1 PW Package, 16-Pin TSSOP (Top View)

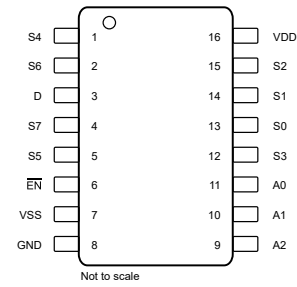


图 6-2. TMUX4051-Q1 DYY Package, 16-Pin SOT-23-THIN (Top View)

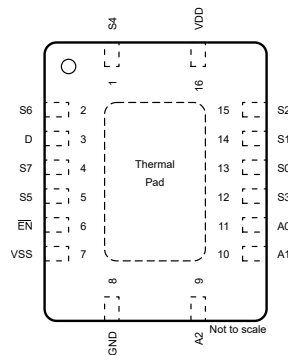


图 6-3. TMUX4051-Q1 BQB Package, 16-Pin WQFN (Top View)

表 6-1. Pin Functions TMUX4051-Q1

PIN		TYPE ⁽¹⁾	DESCRIPTION ⁽²⁾
NAME	NO.		
S4	1	I/O	Source pin 4. Signal path can be an input or output.
S6	2	I/O	Source pin 6. Signal path can be an input or output.
D	3	I/O	Drain pin (common). Signal path can be an input or output.
S7	4	I/O	Source pin 7. Signal path can be an input or output.
S5	5	I/O	Source pin 5. Signal path can be an input or output.
EN	6	I	Active low logic enable. When this pin is high, all switches are turned off. 节 9.3.5 shows how when this pin is low, the A[2:0] address inputs determine which switch is turned on.
V _{SS}	7	P	Negative power supply. This pin is the most negative power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μF to 10 μF between V _{SS} and GND.
GND	8	P	Ground (0 V) reference
A2	9	I	Address line 2. 节 9.3.5 shows how A2 controls the switch configuration.
A1	10	I	Address line 1. 节 9.3.5 shows how A1 controls the switch configuration.
A0	11	I	Address line 0. 节 9.3.5 shows how A0 controls the switch configuration.
S3	12	I/O	Source pin 3. Signal path can be an input or output.
S0	13	I/O	Source pin 0. Signal path can be an input or output.
S1	14	I/O	Source pin 1. Signal path can be an input or output.
S2	15	I/O	Source pin 2. Signal path can be an input or output.
V _{DD}	16	P	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μF to 10 μF between V _{DD} and GND.
Thermal pad		—	The thermal pad is not connected internally. It is recommended that the pad be left floating or tied to GND.

(1) I = input, O = output, I/O = input and output, P = power.

(2) Refer to 节 9.3.4 for what to do with unused pins.

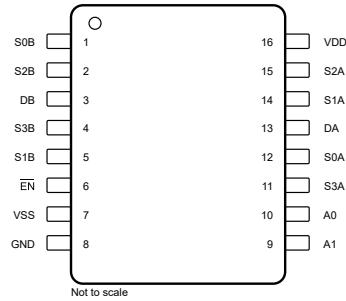


图 6-4. TMUX4052-Q1 PW Package, 16-Pin TSSOP (Top View)

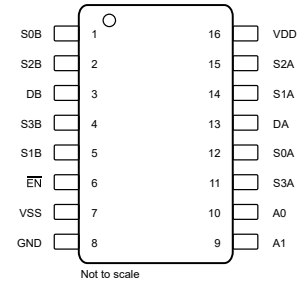


图 6-5. TMUX4052-Q1 DYY Package, 16-Pin SOT-23-THIN (Top View)

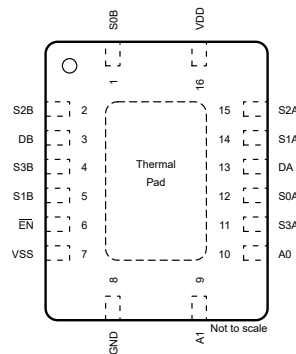


图 6-6. TMUX4052-Q1 BQB Package, 16-Pin WQFN (Top View)

表 6-2. Pin Functions TMUX4052-Q1

PIN		TYPE ⁽¹⁾	DESCRIPTION ⁽²⁾
NAME	NO.		
S0B	1	I/O	Source pin 0 of mux B. Can be an input or output.
S2B	2	I/O	Source pin 2 of mux B. Can be an input or output.
DB	3	I/O	Drain pin (common) of mux B. Can be an input or output.
S3B	4	I/O	Source pin 3 of mux B. Can be an input or output.
S1B	5	I/O	Source pin 1 of mux B. Can be an input or output.
EN	6	I	Active low logic enable. When this pin is high, all switches are turned off. When this pin is low, the A[1:0] address inputs determine which switch is turned on.
V _{SS}	7	P	Negative power supply. This pin is the most negative power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V _{SS} and GND.
GND	8	P	Ground (0 V) reference
A1	9	I	Address line 1. 节 9.3.5 shows how A1 controls the switch configuration.
A0	10	I	Address line 0. 节 9.3.5 shows how A0 controls the switch configuration.
S3A	11	I/O	Source pin 3 of mux A. Can be an input or output.
S0A	12	I/O	Source pin 0 of mux A. Can be an input or output.
DA	13	I/O	Drain pin (common) of mux A. Can be an input or output.
S1A	14	I/O	Source pin 1 of mux A. Can be an input or output.
S2A	15	I/O	Source pin 2 of mux A. Can be an input or output.
V _{DD}	16	P	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V _{DD} and GND.
Thermal pad		—	The thermal pad is not connected internally. It is recommended that the pad be left floating or tied to GND.

(1) I = input, O = output, I/O = input and output, P = power.

(2) Refer to 节 9.3.4 for what to do with unused pins.

ADVANCE INFORMATION

7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾ ⁽²⁾

		MIN	MAX	UNIT
$V_{DD} - V_{SS}$	Supply voltage		28	V
V_{DD}		- 0.5	28	V
V_{SS}		- 28	0.5	V
V_{SEL} or V_{EN}	Logic control input pin voltage (\overline{EN} , Ax, SELx)	- 0.5	28	V
I_{SEL} or I_{EN}	Logic control input pin current (\overline{EN} , Ax, SELx)	- 0.5	28	mA
V_S or V_D	Source or drain voltage (Sx, D)	$V_{SS} - 0.5$	$V_{DD} + 0.5$	V
I_{IK}	Diode clamp current ⁽³⁾	- 30	30	mA
I_S or $I_D (CONT)$	Source or drain continuous current (Sx, D)	- 10	10	mA
T_J	Junction temperature		150	°C
T_{stg}	Storage temperature	- 65	150	°C

- (1) Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If briefly operating outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) All voltages are with respect to ground, unless otherwise specified.
- (3) Pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.

7.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	All pins	±2000
		Charged device model (CDM), per AEC Q100-011	All pins	±750

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

7.3 Thermal Information: TMUX4051-Q1

THERMAL METRIC ⁽¹⁾		TMUX4051-Q1			UNIT
		PW (TSSOP)	DYY (SOT)	BQB (WQFN)	
		16 PINS	16 PINS	16 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	116.5	TBD	TBD	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	47.2	TBD	TBD	°C/W
R _{θJB}	Junction-to-board thermal resistance	63.0	TBD	TBD	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	6.4	TBD	TBD	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	62.1	TBD	TBD	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	TBD	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

7.4 Thermal Information: TMUX4052-Q1

THERMAL METRIC ⁽¹⁾		TMUX4052-Q1			UNIT
		PW (TSSOP)	DYY (SOT)	BQB (WQFN)	
		16 PINS	16 PINS	16 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	116.5	TBD	TBD	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	47.2	TBD	TBD	°C/W
R _{θJB}	Junction-to-board thermal resistance	63.0	TBD	TBD	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	6.4	TBD	TBD	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	62.1	TBD	TBD	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	TBD	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

7.5 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{DD} - V _{SS} ⁽¹⁾	Power supply voltage differential	3		24	V
V _{DD}	Positive power supply voltage	3		24	V
V _S or V _D	Signal path input/output voltage (source or drain pin) (Sx, D)	V _{SS}		V _{DD}	V
V _{Ax} or V _{EN}	Address or enable pin voltage	0		V _{DD}	V
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)	- 10		10	mA
T _A	Ambient temperature	- 55		125	°C

(1) V_{DD} and V_{SS} can be any value as long as 3 V ≤ (V_{DD} - V_{SS}) ≤ 24 V, and the minimum V_{DD} is met.

7.6 Electrical Characteristics

Over operating free-air temperature range,
Typical at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS				MIN	TYP	MAX	UNIT
	CONDITION	V_{DD}	V_{SS}	T_A				
POWER SUPPLY								
Supply current I_{DD}	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	5 V	0 V	- 55°C			50	μA
				25°C		20	50	
				85°C			60	
				125°C			60	
	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	10 V	0 V	- 55°C			50	
				25°C		20	50	
				85°C			300	
				125°C			300	
	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	24 V	0 V	- 55°C			100	
				25°C		25	100	
				85°C			300	
				125°C			300	
	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	5 V	- 5 V	- 55°C			100	
				25°C		22	100	
				85°C			300	
				125°C			300	
	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	12 V	- 12 V	- 55°C			100	
				25°C		25	100	
				85°C			300	
				125°C			300	
Negative supply current I_{SS}	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	5 V	- 5 V	- 55°C			15	μA
				25°C		8	18	
				85°C			20	
				125°C			22	
	Address inputs = 0 V, 5 V, or V_{DD} $\overline{EN} = 0\text{ V}$	12 V	- 12 V	- 55°C			18	
				25°C		8	22	
				85°C			26	
				125°C			26	
I_{DD} disable	TMUX4051 $\overline{EN} = 5\text{ V}$ or V_{DD}	All	25°C			12	μA	
			- 55°C to 125°C			30		
	TMUX4052 $\overline{EN} = 5\text{ V}$ or V_{DD}		25°C			14		
			- 55°C to 125°C			30		

ADVANCE INFORMATION

Over operating free-air temperature range,
Typical at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

ADVANCE INFORMATION

PARAMETER	TEST CONDITIONS				MIN	TYP	MAX	UNIT
	CONDITION	V_{DD}	V_{SS}	T_A				
ANALOG SWITCH								
R_{ON} Source to Drain ON-Resistance	$V_S = V_{SS}$ to V_{DD} $I_D = -1\text{ mA}$	5 V	0 V	-55°C			800	Ω
				25°C		75	1050	
				85°C			1200	
				125°C			1300	
	$V_S = V_{SS}$ to V_{DD} $I_D = -1\text{ mA}$	10 V	0 V	-55°C			310	
				25°C		60	400	
				85°C			520	
				125°C			550	
	$V_S = V_{SS}$ to V_{DD} $I_D = -1\text{ mA}$	24 V	0 V	-55°C			200	
				25°C		60	240	
				85°C			300	
				125°C			300	
	$V_S = V_{SS}$ to V_{DD} $I_D = -1\text{ mA}$	5 V	-5 V	-55°C			310	
				25°C		60	400	
				85°C			520	
				125°C			550	
	$V_S = V_{SS}$ to V_{DD} $I_D = -1\text{ mA}$	12 V	-12 V	-55°C			200	
				25°C		60	240	
				85°C			300	
				125°C			300	
ΔR_{ON} ON-Resistance Mismatch Between Channels	$V_S = V_{SS}$ to V_{DD} $I_D = -1\text{ mA}$	5 V	0 V	25°C			4	Ω
							2	
							2	
							3	
							2	
$I_{S(OFF)}$ $I_{D(OFF)}$	Switch State is off $V_S = V_{SS} / V_{DD}$ $V_D = V_{DD} / V_{SS}$	24 V	0 V	25°C		± 0.1	± 100	nA
				-55°C to 85°C			± 800	
				-55°C to 125°C			± 1000	
I_{ON}	Switch State is on $V_S = V_D = V_{SS}$ or V_{DD}	24 V	0 V	25°C		± 0.1		nA
				-55°C to 85°C			± 800	
				-55°C to 125°C			± 1000	
LOGIC INPUTS (ADDRESS / ENABLE pins)								
V_{IH}	Input High Voltage	All		-55°C to 125°C	1.35		V_{DD}	V
V_{IL}	Input Low Voltage	All		-55°C to 125°C	0		0.8	V

Over operating free-air temperature range,
Typical at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT
	CONDITION	V_{DD}	V_{SS}				
I_{IH} I_{IL} Logic Input Current	$V_{LOGIC} = 0\text{ V}, 5\text{ V}, \text{ or } V_{DD}$	All		25°C	0.5		μA
		All		-55°C to 125°C	-1	1	
C_{IN}		All		25°C	3		pF

AC Performance Characteristics

Typical at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS				$T_A = -55^\circ\text{C to } 125^\circ\text{C}$			UNIT
	CONDITION	V_{DD}	V_{SS}	GPN	MIN	TYP	MAX	
DYNAMIC CHARACTERISTICS								
$C_{S(OFF)}$	$V_S = (V_{DD} + V_{SS}) / 2\text{ V}$ $f = 1\text{ MHz}$	24 V	0 V	All		3		pF
$C_{D(OFF)}$	$V_S = (V_{DD} + V_{SS}) / 2\text{ V}$ $f = 1\text{ MHz}$	24 V	0 V	TMUX4051-Q1		10		pF
		24 V	0 V	TMUX4052-Q1		5		
$C_{S(ON)}$ $C_{D(ON)}$	$V_S = (V_{DD} + V_{SS}) / 2\text{ V}$ $f = 1\text{ MHz}$	24 V	0 V	TMUX4051-Q1		11		pF
		24 V	0 V	TMUX4052-Q1		7		
BW (-3dB) Channel ON	$V_{BIAS} = (V_{DD} - V_{SS}) / 2$ ⁽¹⁾ $V_S = 200\text{ mVpp}$ $R_L = 50\ \Omega, C_L = 5\text{ pF}$	24 V	0 V	TMUX4051-Q1		400		MHz
		24 V	0 V	TMUX4052-Q1		500		
Off Isolation Channel OFF	$V_{BIAS} = (V_{DD} - V_{SS}) / 2$ ⁽¹⁾ $V_S = 200\text{ mVpp}$ $R_L = 50\ \Omega, C_L = 5\text{ pF}$ $f = 1\text{ MHz}$	24 V	0 V	TMUX4051-Q1		-85		dB
		24 V	0 V	TMUX4052-Q1		-85		
Crosstalk	$V_{BIAS} = (V_{DD} - V_{SS}) / 2$ ⁽¹⁾ $V_S = 200\text{ mVpp}$ $R_L = 50\ \Omega, C_L = 5\text{ pF}$ $f = 1\text{ MHz}$	24 V	0 V	TMUX4051-Q1		-90		dB
		24 V	0 V	TMUX4052-Q1		-90		
Charge Injection	$V_S = (V_{DD} - V_{SS}) / 2$ $R_S = 0\ \Omega, C_L = 100\text{ pF}$	24 V	0 V	TMUX4051-Q1		5		pC
		24 V	0 V	TMUX4052-Q1		3		

(1) Peak-to-Peak voltage symmetrical about $(V_{DD} - V_{SS}) / 2$.

7.7 Timing Characteristics

Over operating free-air temperature range,
Typical at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS				MIN	TYP	MAX	UNIT	
		CONDITION	V_{DD}	V_{SS}	T_A					
Prop Delay	Signal Input to Signal Output	$V_S = V_{SS}$ to V_{DD}	5 V	0 V	25°C		4	60	ns	
			10 V	0 V	25°C		3	30		
			24 V	0 V	25°C		2	20		
			5 V	- 5 V	25°C		3	20		
			12 V	- 12 V	25°C		2	20		
t_{TRAN}	Address-to-Signal OUT Transition time between inputs	$t_r, t_f = 20$ ns, $C_L = 50$ pF, $R_L = 10$ k Ω	5 V	0 V	25°C		125		ns	
					- 55°C to +125°C			700		
			10 V	0 V	25°C		120			ns
					- 55°C to +125°C			300		
			24 V	0 V	25°C		130			ns
					- 55°C to +125°C			250		
			5 V	- 5 V	25°C		125			ns
					- 55°C to +125°C			300		
			12 V	- 12 V	25°C		130			ns
					- 55°C to +125°C			250		
$t_{ON(EN)}$	Enable-to-Signal OUT Channel turning ON	$t_r, t_f = 20$ ns, $C_L = 50$ pF, $R_L = 10$ k Ω	5 V	0 V	25°C		110		ns	
					- 55°C to +125°C			700		
			10 V	0 V	25°C		100			ns
					- 55°C to +125°C			300		
			24 V	0 V	25°C		115			ns
					- 55°C to +125°C			250		
			5 V	- 5 V	25°C		110			ns
					- 55°C to +125°C			300		
			12 V	- 12 V	25°C		115			ns
					- 55°C to +125°C			250		
$t_{OFF(EN)}$	Enable-to-Signal OUT Channel turning OFF	$t_r, t_f = 20$ ns, $C_L = 50$ pF, $R_L = 10$ k Ω	5 V	0 V	25°C		100		ns	
					- 55°C to +125°C			400		
			10 V	0 V	25°C		100			ns
					- 55°C to +125°C			200		
			24 V	0 V	25°C		90			ns
					- 55°C to +125°C			180		
			5 V	- 5 V	25°C		150			ns
					- 55°C to +125°C			200		
			12 V	- 12 V	25°C		150			ns
					- 55°C to +125°C			180		

ADVANCE INFORMATION

Over operating free-air temperature range,
Typical at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
		CONDITION	V _{DD}	V _{SS}				
t _{BBM}		C _L = 15 pF, R _L = 10 k Ω	5 V	0 V	25°C	80		ns
					- 55°C to +125°C	1		
			10 V	0 V	25°C	40		
					- 55°C to +125°C	1		
			5 V	- 5 V	25°C	75		
					- 55°C to +125°C	1		
			12 V	- 12 V	25°C	100		
					- 55°C to +125°C	1		
			24 V	0 V	25°C	75		
					- 55°C to +125°C	1		

ADVANCE INFORMATION

8 Parameter Measurement Information

8.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. The measurement setup used to measure R_{ON} is shown in the following figure. 图 8-1 shows how the R_{ON} is computed with $R_{ON} = V / I_{SD}$, and the voltage (V) and current (I_{SD}) are measured using this setup.

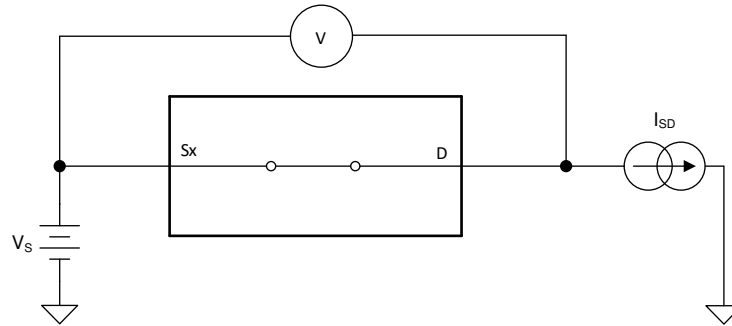


图 8-1. On-Resistance Measurement Setup

8.2 Off-Leakage Current

There are two types of leakage currents associated with a switch during the off state:

1. Source off-leakage current.
2. Drain off-leakage current.

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol $I_{D(OFF)}$.

图 8-2 shows the setup used to measure both off-leakage currents.

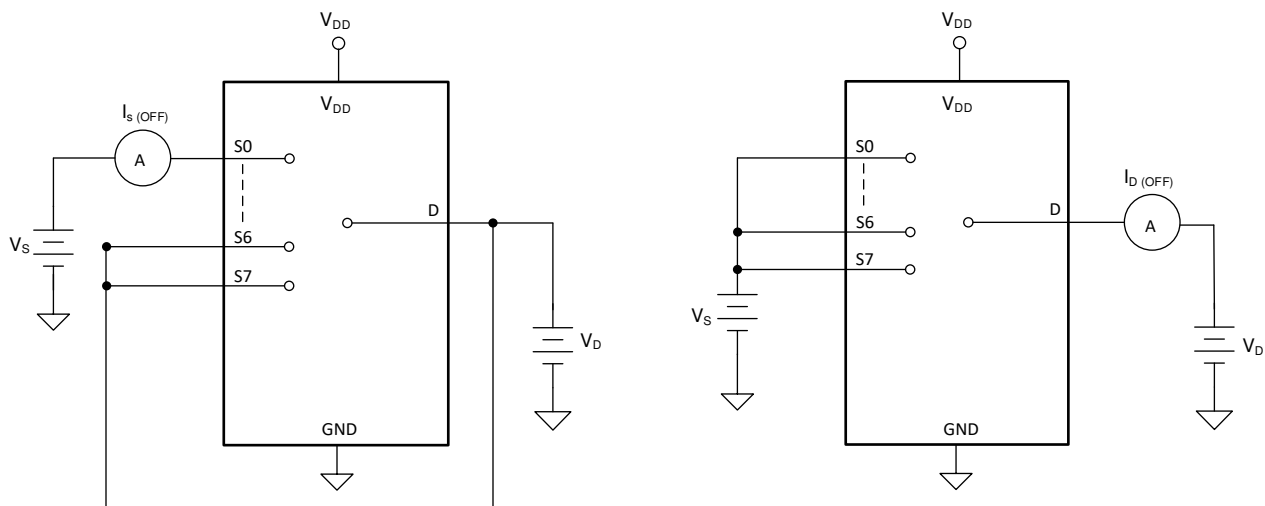


图 8-2. Off-Leakage Measurement Setup

8.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol $I_{S(ON)}$.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol $I_{D(ON)}$.

Either the source pin or drain pin is left floating during the measurement. 图 8-3 shows the circuit used for measuring the on-leakage current, denoted by $I_{S(ON)}$ or $I_{D(ON)}$.

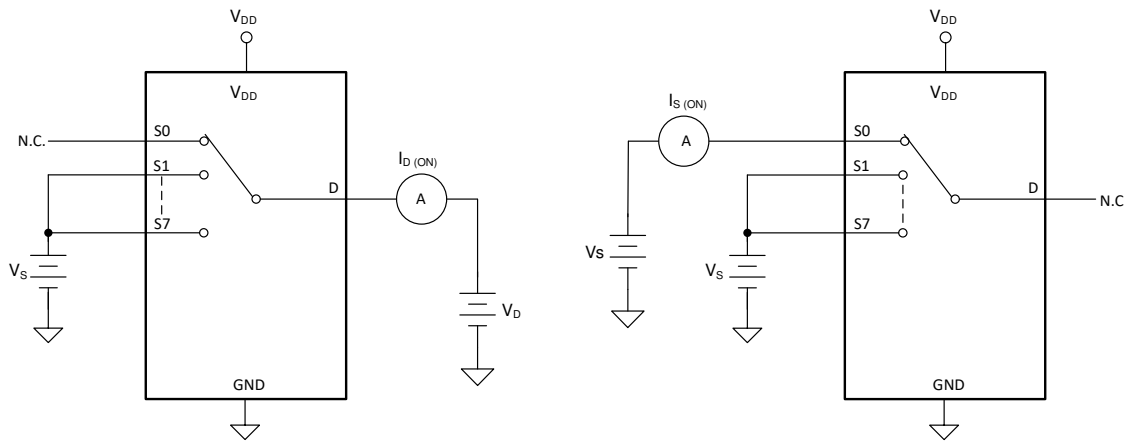


图 8-3. On-Leakage Measurement Setup

8.4 Charge Injection

Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q_C . 图 8-4 shows the setup used to measure charge injection from source (Sx) to drain (D).

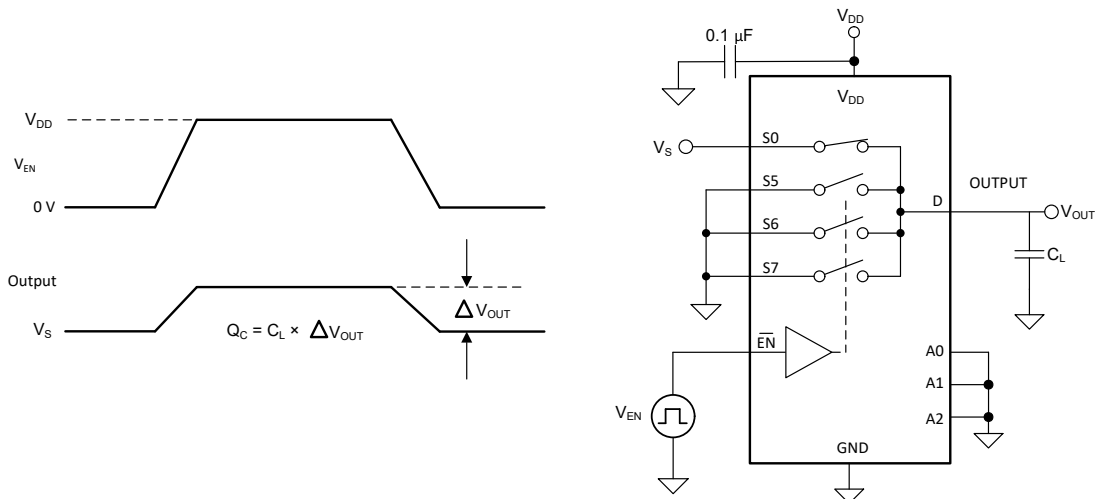


图 8-4. Charge-Injection Measurement Setup

8.5 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (D) of the device when a signal is applied to the source pin (Sx) of an off-channel. 图 8-5 shows the setup used to measure, and the equation to compute off isolation.

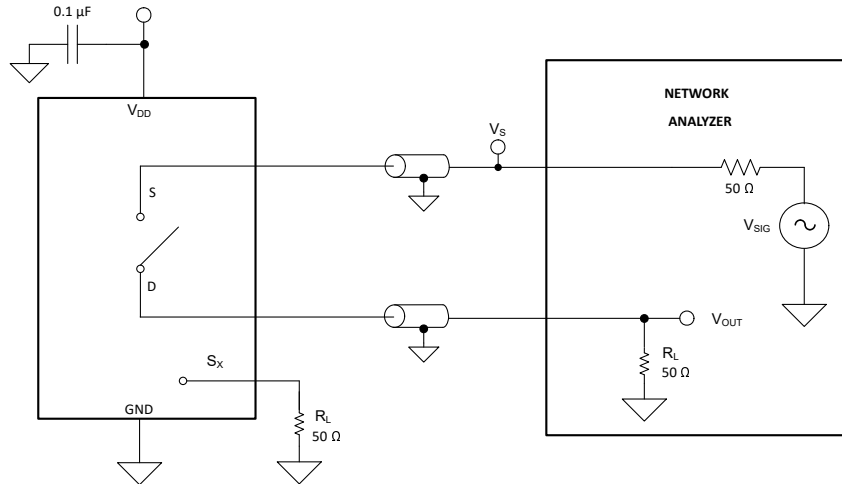


图 8-5. Off Isolation Measurement Setup

$$\text{Off Isolation} = 20 \cdot \text{Log} \left(\frac{V_{\text{OUT}}}{V_{\text{S}}} \right) \quad (1)$$

8.6 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. 图 8-6 shows the setup used to measure, and the equation used to compute crosstalk.

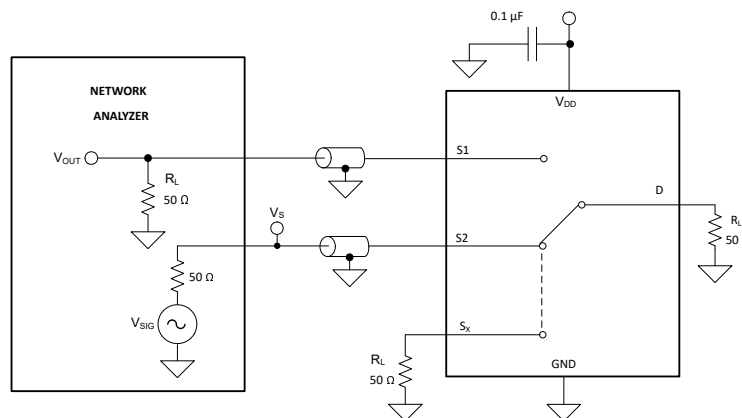


图 8-6. Channel-to-Channel Crosstalk Measurement Setup

$$\text{Channel-to-Channel Crosstalk} = 20 \cdot \text{Log} \left(\frac{V_{\text{OUT}}}{V_{\text{S}}} \right) \quad (2)$$

8.7 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (D) of the device. [图 8-7](#) shows the setup used to measure bandwidth.

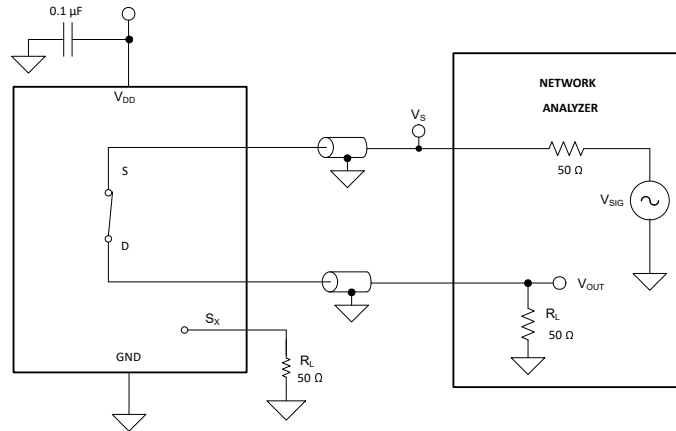


图 8-7. Bandwidth Measurement Setup

$$\text{Attenuation} = 20 \cdot \text{Log} \left(\frac{V_2}{V_1} \right)$$

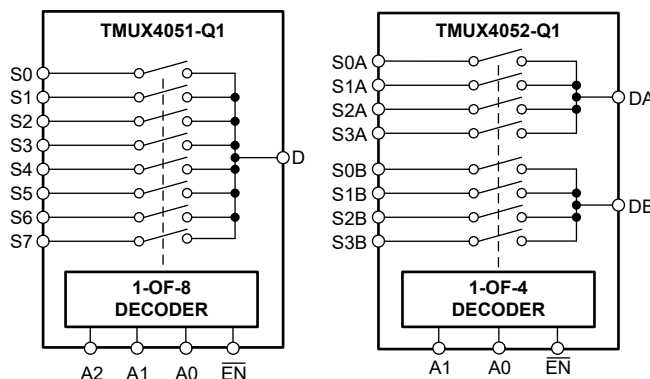
(3)

9 Detailed Description

9.1 Overview

The TMUX4051-Q1 is an 8:1, single-ended (1-channel) mux while the TMUX4052-Q1 is a 4:1, differential (2-channel) multiplexer. Each channel is turned on or turned off based on the state of the address lines and enable pin.

9.2 Functional Block Diagram



9.3 Feature Description

9.3.1 Bidirectional Operation

The TMUX4051-Q1 and TMUX4052-Q1 devices conduct equally well from source (Sx) to drain (Dx) or from drain (Dx) to source (Sx). Each signal path has very similar characteristics in both directions so they can be used as both multiplexers and demultiplexer to support both analog and digital signals.

9.3.2 Rail-to-Rail Operation

The valid signal path input and output voltage for the TMUX4051-Q1 and TMUX4052-Q1 ranges from V_{SS} to V_{DD} .

9.3.3 1.8 V Logic Compatible Inputs

The TMUX4051-Q1 and TMUX4052-Q1 support 1.8-V logic compatible control for all logic control inputs. 1.8-V logic level inputs allows the multiplexers to interface with processors that have lower logic I/O rails and eliminates the need for an external voltage translator, which saves both space and BOM cost. For more information on 1.8-V logic implementations refer to [Simplifying Design with 1.8 V logic Muxes and Switches](#).

9.3.4 Device Functional Modes

When the \overline{EN} pin of the TMUX405x-Q1 devices is pulled low, one of the switches is closed based on the state of the address or select pins. When the \overline{EN} pin is pulled high, all the switches are in an open state regardless of the state of the address or select pins.

Unused logic control pins must be tied to GND or V_{DD} to ensure the device does not consume additional current as highlighted in [Implications of Slow or Floating CMOS Inputs](#). Unused signal path inputs (Sx and Dx) should be connected to GND.

9.3.5 Truth Tables

表 9-1 和 表 9-2 show the truth tables for the TMUX4051-Q1 respectively.

表 9-1. TMUX4051-Q1 Truth Table

EN	A2	A1	A0	Selected Signal Path Connected To Drain (D) Pin
0	0	0	0	S0
0	0	0	1	S1
0	0	1	0	S2
0	0	1	1	S3
0	1	0	0	S4
0	1	0	1	S5
0	1	1	0	S6
0	1	1	1	S7
1	X ⁽¹⁾	X ⁽¹⁾	X ⁽¹⁾	All inputs are unselected (HI-Z)

(1) X denotes *do not care*.

表 9-2. TMUX4052-Q1 Truth Table

EN	A1	A0	Selected Signal Path Connected To Drain (DA and DB) Pins
0	0	0	S0A to DA S0B to DB
0	0	1	S1A to DA S1B to DB
0	1	0	S2A to DA S2B to DB
0	1	1	S3A to DA S3B to DB
1	X ⁽¹⁾	X ⁽¹⁾	All inputs are unselected (HI-Z)

(1) X denotes *do not care*.

10 Application and Implementation

备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

10.1 Application Information

The TMUX405x-Q1 devices offer good system performance across a wide operating supply (3 V to 24 V). These devices include 1.8 V logic compatible control input pins that enable operation in systems with 1.8 V I/O rails. These features make the TMUX40xx a family of general purpose multiplexers and switches that can reduce system complexity, board size, and overall system cost.

10.2 Typical Application

One useful application to take advantage of the TMUX405x-Q1 features is multiplexing various signals into an ADC that is integrated into an MCU. Utilizing an integrated ADC in an MCU allows a system to minimize cost with a potential tradeoff of system performance when compared to an external ADC. The multiplexer allows for multiple inputs or sensors to be monitored with a single ADC pin of the device, which is critical in systems with limited I/O. The TMUX4052-Q1 is suitable for similar design example using differential signals, or as two 4:1 multiplexers.

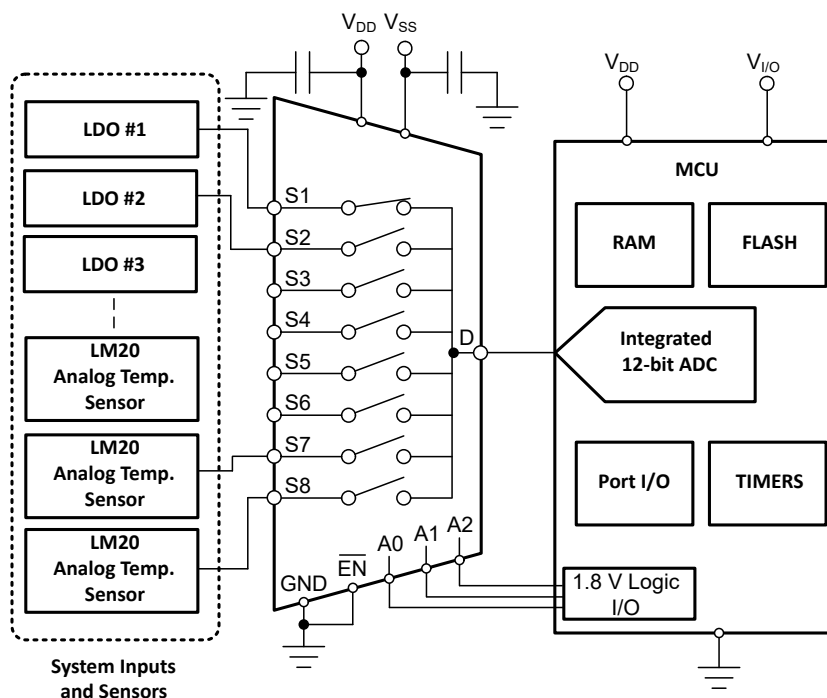


图 10-1. Multiplexing Signals to an Integrated ADC with TMUX4051-Q1

10.3 Design Requirements

表 10-1 lists the parameters that must be used for this design example.

表 10-1. Design Parameters

PARAMETERS	VALUES
Supply (V_{DD})	12 V
I/O signal range	0 V to V_{DD} (rail-to-rail)
Control logic thresholds	1.8 V compatible

10.4 Detailed Design Procedure

The TMUX4051-Q1 and TMUX4052-Q1 can be operated without any external components except for the supply decoupling capacitors. The MCU can control the enable and address pins through GPIOs to toggle between various inputs of the multiplexer. If the desired power-up state is disabled, the enable pin should have a pull-up resistor. The enable pin should be connected to ground if the functionality is not required in the system. All inputs being muxed to the ADC of the MCU must fall within the *Recommended Operating Conditions*, including signal range and continuous current. For this design with a supply of 12 V, the signal range can be 0 V to 12 V.

11 Power Supply Recommendations

The TMUX4051-Q1 and TMUX4052-Q1 devices operate across a wide supply range of 3 V to 24 V.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the supply pins to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1 μ F to 10 μ F from V_{DD} to ground and V_{SS} to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground planes.

12 Layout

12.1 Layout Guidelines

Route high-speed signals using minimal vias and corners, which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

图 12-1 illustrates an example of a PCB layout with the TMUX4051-Q1 and TMUX4052-Q1. Some key considerations are as follows:

- Decouple the V_{DD} and V_{SS} pins with a 0.1- μ F capacitor, placed as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient.
- Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.

12.2 Layout Example

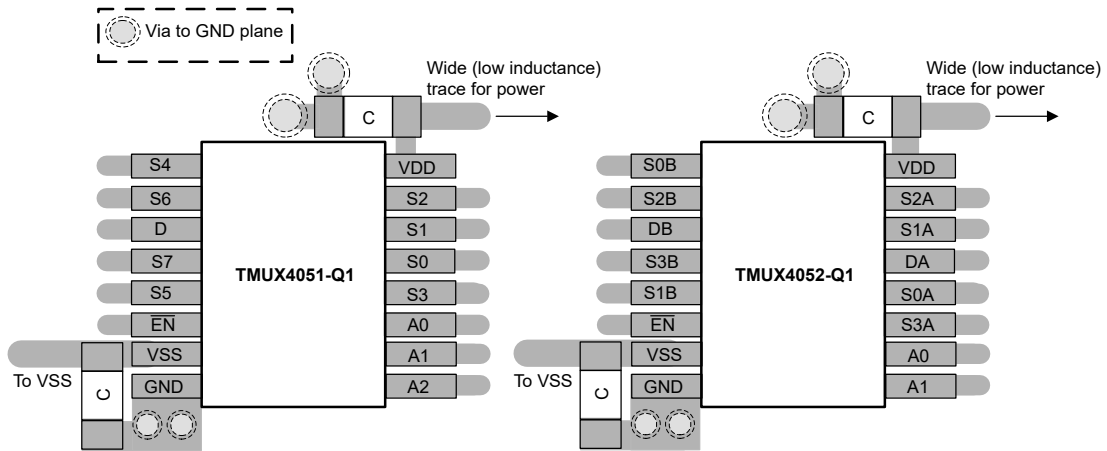


图 12-1. TMUX4051-Q1 and TMUX4052-Q1 Layout Example

13 Device and Documentation Support

13.1 Documentation Support

13.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, [Simplifying Design with 1.8 V logic Muxes and Switches application brief](#)
- Texas Instruments, [QFN/SON PCB Attachment application report](#)
- Texas Instruments, [Quad Flatpack No-Lead Logic Packages application report](#)

13.2 接收文档更新通知

要接收文档更新通知，请导航至 [ti.com](https://www.ti.com) 上的器件产品文件夹。点击 [订阅更新](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

13.3 支持资源

TI E2E™ [支持论坛](#) 是工程师的重要参考资料，可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [《使用条款》](#)。

13.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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13.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

13.6 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

14 Mechanical, Packaging, and Orderable Information

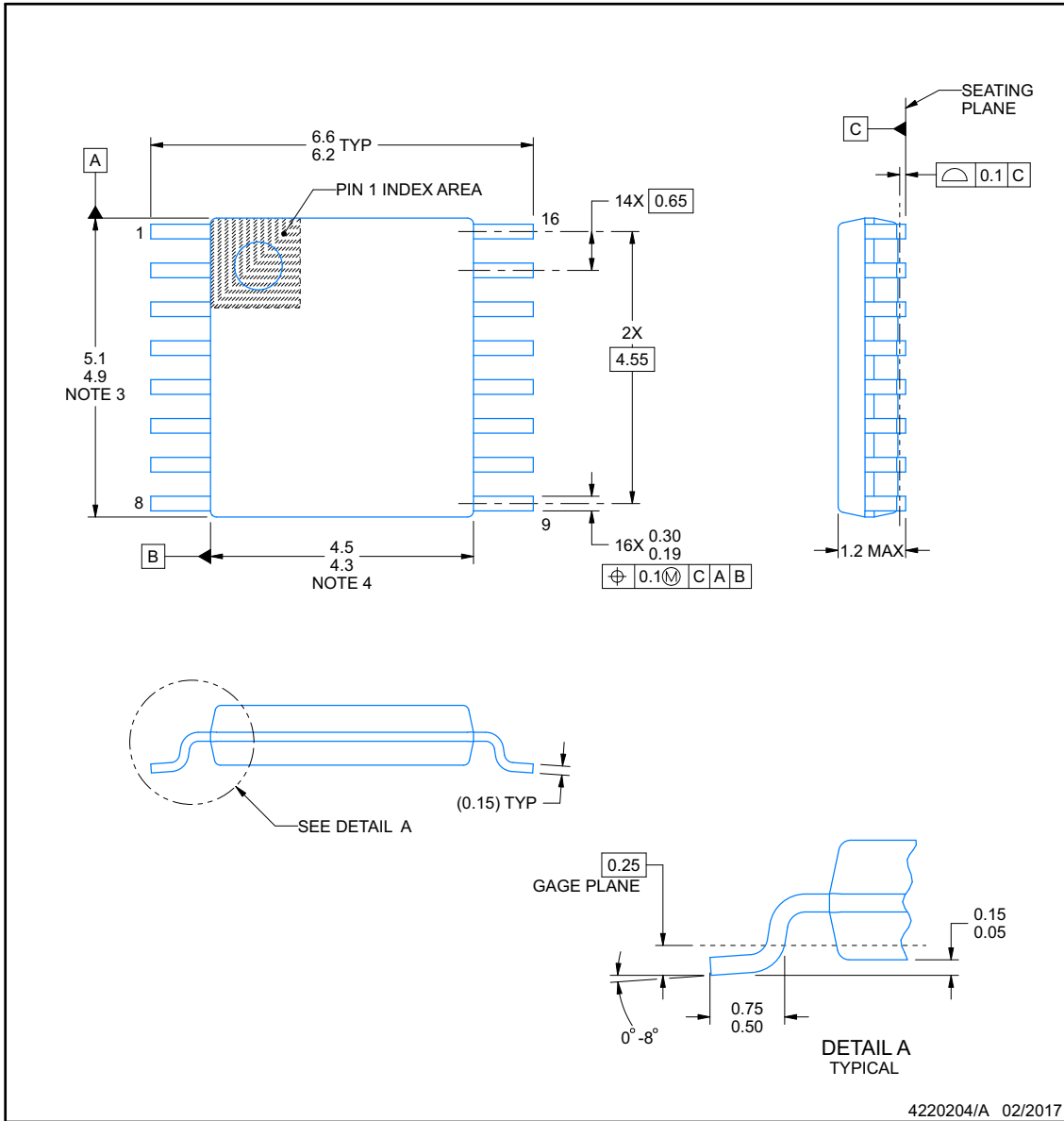
The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PW0016A



PACKAGE OUTLINE
TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

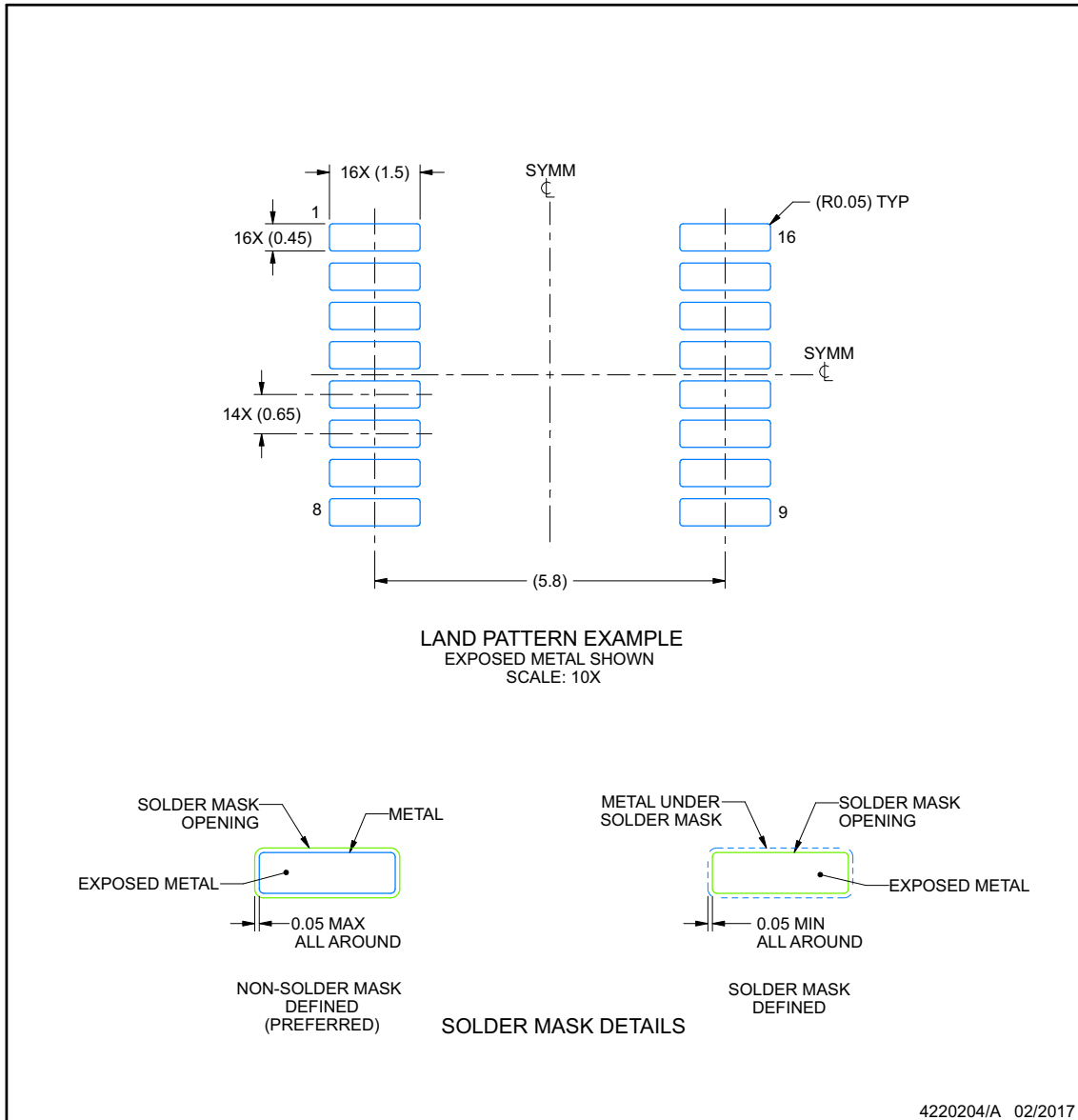
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

EXAMPLE BOARD LAYOUT

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

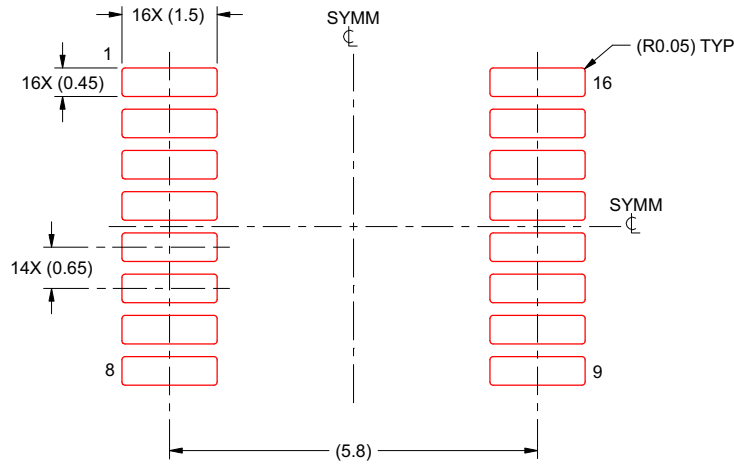
ADVANCE INFORMATION

EXAMPLE STENCIL DESIGN

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

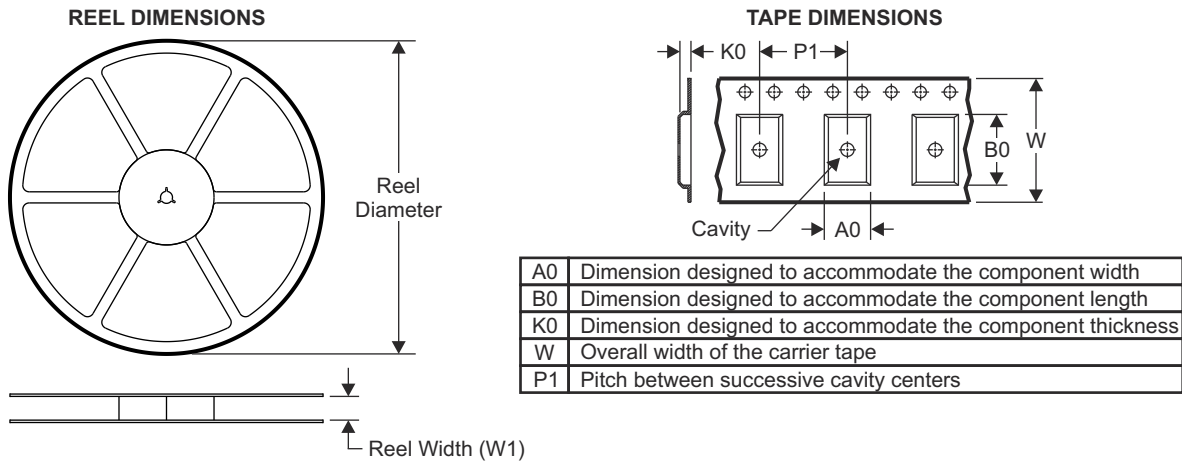
4220204/A 02/2017

NOTES: (continued)

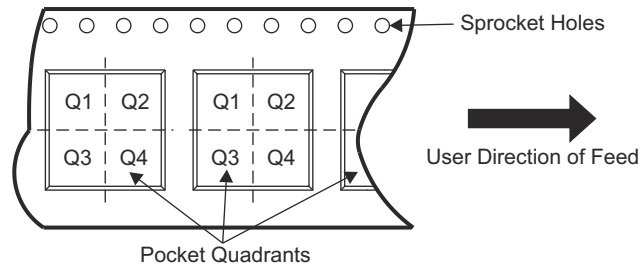
8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

ADVANCE INFORMATION

14.1 Tape and Reel Information



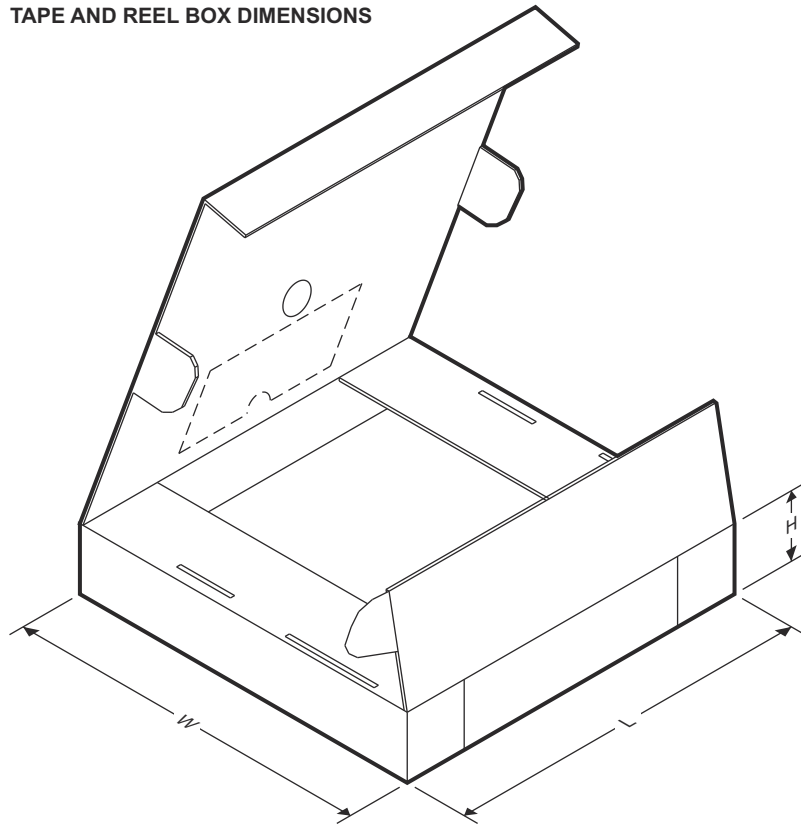
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TMUX4051PWRQ1	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TMUX4051DYRQ1	SOT-23-THIN	DYY	16	3000	330.0	12.4	4.8	3.6	1.6	8.0	12.0	Q3
TMUX4051BQBRQ1	WQFN	BQB	16	3000	180.0	12.4	2.8	3.8	1.2	4.0	12.0	Q1
TMUX4052PWRQ1	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TMUX4052DYRQ1	SOT-23-THIN	DYY	16	3000	330.0	12.4	4.8	3.6	1.6	8.0	12.0	Q3
TMUX4052BQBRQ1	WQFN	BQB	16	3000	180.0	12.4	2.8	3.8	1.2	4.0	12.0	Q1

ADVANCE INFORMATION

TAPE AND REEL BOX DIMENSIONS



ADVANCE INFORMATION

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TMUX4051PWRQ1	TSSOP	PW	16	2000	356.0	356.0	35.0
TMUX4051DYRQ1	SOT-23-THIN	DYY	16	3000	336.6	336.6	31.8
TMUX4051BQBRQ1	WQFN	BQB	16	3000	210.0	185.0	35.0
TMUX4052PWRQ1	TSSOP	PW	16	2000	356.0	356.0	35.0
TMUX4052DYRQ1	SOT-23-THIN	DYY	16	3000	336.6	336.6	31.8
TMUX4052BQBRQ1	WQFN	BQB	16	3000	210.0	185.0	35.0

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
PTMUX4051DYRQ1	ACTIVE	SOT-23-THIN	DYY	16	3000	TBD	Call TI	Call TI	-55 to 125		Samples
PTMUX4051PWRQ1	ACTIVE	TSSOP	PW	16	2500	TBD	Call TI	Call TI	-55 to 125		Samples
PTMUX4052DYRQ1	ACTIVE	SOT-23-THIN	DYY	16	3000	TBD	Call TI	Call TI	-55 to 125		Samples
PTMUX4052PWRQ1	ACTIVE	TSSOP	PW	16	2000	TBD	Call TI	Call TI	-55 to 125		Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF TMUX4051-Q1, TMUX4052-Q1 :

- Catalog : [TMUX4051](#), [TMUX4052](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

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